LINEAR TECHNOLOGY

RELIABILITY DATA

LT685 / LT6650 / LT6700

6/17/04

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS (1) AT +125°C	NUMBER OF (2) FAILURES
HERMETIC	57	8805	8805	379.21	0
PLASTIC DIP	199	9316	9316	1,916.77	0
SOIC/SOT/MSOP	153	0337	0421	153.00	0
	409			2,448.98	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	150	9410	0138	3.60	0
SOIC/SOT/MSOP	50	0320	0320	1.20	0
	200			4.80	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	100	9410	0138	10.00	0
SOIC/SOT/MSOP	50	0320	0320	5.00	0
	150			15.00	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	50	9512	9512	5.00	0
SOIC/SOT/MSOP	50	0320	0320	5.00	0
	100			10.00	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.75 FITS

(3) Mean Time Between Failures in Years = 152,103

Note: 1 FIT = 1 Failure in One Billion Hours.